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Structure/Property Relationships for Metal/Metal Interfaces

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Structure/Property Relationships for Metal/Metal Interfaces

Symposium held April 29-May 1, 1991, Anaheim, California, U.S.A.

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Structure/Property Relationships for Metal/Metal Interfaces

Preface

This volume contains the Proceedings of the Symposium on Structure/Property Relationships for Metal/Metal Interfaces held at the 1991 Spring Meeting of the Materials Research Society. The forty-four papers published here, of which thirteen were invited, address this topic by means of experimental and theoretical investigations on a variety of interfacial systems that are found or can be fabricated in metals.

The central theme of the Symposium was the relationship between the physical properties of metallic materials containing interfaces and the detailed atomic structure of those interfaces. As is evidenced by the contributions to this volume, this theme actually encompasses quite a number of active research fields. When categorized by an interest in interfacial structure, these fields include metal/vacuum surface physics and surface layer characterization, x-ray diffractometry of films and superlattices, TEM characterization of orientational relationships in superlattices, grain boundaries, and dissimilar metal interfaces, and analytical microscopy of grain boundaries and dissimilar metal interfaces. As categorized by an interest in properties, these fields include elastic and plastic properties of superlattices, grain boundaries, and generic interfaces, dislocation motion through interfaces, fracture, segregation, and precipitation at grain boundaries and at dissimilar metal interfaces, x-ray optical properties of multilayers, and magnetic properties of superlattices.

From this diversity of subject matter it is clear that the role interfaces play in determining the properties of materials can be considerable. This is apparent in both basic science investigations and modern technological applications especially where metallic thin films, superlattices and nanocrystals are involved since their structures are composed mainly of interfaces. Due to the sheer breadth of the subject matter presented here and at the symposium, it is difficult to simply summarize all of the outstanding work and new observations. Nevertheless, one underlying aspect continues to dominate our attempts at understanding the impact of interfacial structure on properties. This is the ongoing development and improvement of our characterization tools, which allow us to clearly "see" the atomic structure of the interface. Progress in obtaining a detailed microscopic picture of interfaces, particularly in high-density-interface materials, will continue to be central to our understanding and control of the new physical properties which are observed.

A.D. Romig
D.E. Fowler
P.D. Bristowe

June 1991

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Their generosity is greatly appreciated and it allowed the organizers to focus on making the symposium a successful and smoothly functioning experience for all. Last, but not least, we would like to acknowledge the assistance of Ms. Sandy Ung in the preparation of the Proceedings.

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Contents

PREFACE	ix
ACKNOWLEDGMENTS	xii
MATERIALS RESEARCH SOCIETY SYMPOSIUM PROCEEDINGS	xiii
RECONSTRUCTIONS AND MORPHOLOGICAL INSTABILITIES OF FCC (110) SURFACES J. Sun and Craig Rottman	3
CONCENTRATION-DEPENDENT SURFACE-STATE SHIFTS: Au on Cu(001) J.C. Hansen, M.K. Wagner, and J.G. Tobin	9
*SCANNING TUNNELING MICROSCOPY STUDIES OF METAL/METAL EPITAXIAL GROWTH David D. Chambliss, Shirley Chiang, and Robert J. Wilson	15
*X-RAY PHOTOELECTRON AND AUGER ELECTRON FORWARD-SCATTERING STUDIES OF THE EPITAXIAL GROWTH OF Fe ON Ag(100) William F. Egelhoff, Jr.	27
*QUANTITATIVE X-RAY STRUCTURE DETERMINATION OF SUPER-LATTICES AND INTERFACES Ivan K. Schuller, Eric E. Fullerton, H. Vanderstraeten, and Y. Bruynseraede	41
*IMPLICATIONS OF INTERFACE STRUCTURE ON THE ELASTIC PROPERTIES OF METALLIC MULTILAYERS - THE CASE OF THE SUPERMODULUS EFFECT Alan F. Jankowski	53
*ATOMIC-LEVEL AND EFFECTIVE ELASTIC MODULI AT GRAIN BOUNDARIES I. Alber, J.L. Bassani, M. Khantha, V. Vitek, and G.J. Wang	65
ELASTIC MODULI OF METALLIC MULTILAYERED THIN FILMS Ag/Cu, Al/Cu AND Co/Cu MEASURED BY BRILLOUIN SCATTERING METHOD Toshiya Ito, Ryoichi Yamamoto, and Akira Yoshihara	79
TEMPERATURE DEPENDENCE OF THE ELASTIC BEHAVIOR OF STRUCTURALLY DISORDERED METALLIC SUPERLATTICES J.A. Jaszczak and D. Wolf	85
CONTAMINATION EFFECTS IN Mo/Ni SUPERLATTICES Steven M. Hues and John L. Makous	91

*Invited Paper

ELASTIC PROPERTIES AND STRUCTURAL EVOLUTION OF AgNi SUPERLATTICES	97
B. Rodmacq, V. Pelosin, and J. Hillairet	
*INFLUENCE OF STRUCTURE ON THE SOFT X-RAY OPTICAL PROPERTIES OF METALLIC MULTILAYERS	103
J.M. Slaughter, Patrick A. Kearney, and Charles M. Falco	
INTERFACIAL MIXING IN EPITAXIAL Co/Pt SUPERLATTICES: A SOURCE OF MAGNETOCRYSTALLINE ANISOTROPY	115
R.F.C. Farrow, B.D. Hermsmeier, C.H. Lee, R.F. Marks, E.E. Marinero, C.J. Lin, C.J. Chien, and S.B. Hagstrom	
THE EFFECT OF GRAIN BOUNDARIES AND SUBSTRATE INTERACTIONS WITH HYDROGEN ON THE CVD GROWTH OF DEVICE-QUALITY COPPER	123
A.E. Kaloyeros, C. Dettelbacher, E.T. Eisenbraun, W.A. Lanford, H. Li, J.F. Olowolafe, S. Murarka, F. Pintchovski, Y.-T. Shy, and P.J. Toscano	
*THE REAL-SPACE MULTIPLE-SCATTERING THEORY AND THE ELECTRONIC STRUCTURE OF GRAIN BOUNDARIES	129
Erik C. Sowa, A. Gonis, and X.-G. Zhang	
MAGNETIC AND TRANSPORT PROPERTIES OF Ag/Cr METALLIC SUPERLATTICES	141
Kentaro Kyuno, Yasushi Inoue, Shinzo Ogu, Kazuki Mae, Takeo Kaneko, and Ryoichi Yamamoto	
THE MEASUREMENT OF THERMAL CONDUCTIVITY OF Ag/Al MULTILAYERED FILMS	147
Takeshi Kaizuka, We-Hyo Soe, Ryoichi Yamamoto, and Masanori Ohyama	
MOLECULAR DYNAMICS STUDY OF THERMAL DISORDER IN A BICRYSTAL MODEL	153
Tue Nguyen, Paul S. Ho, Thomas Kwok, Cynthia Nitta, and Sidney Yip	
*DETERMINATION OF ENERGY MINIMA FOR DISSIMILAR METAL INTERFACES	159
Paul Shewmon and Suliman Dregia	
*TEM CHARACTERIZATION OF GRAIN BOUNDARIES IN MAZED BICRYSTAL FILMS OF ALUMINUM	167
U. Dahmen and K.H. Westmacott	
AN ATOMISTIC STUDY OF THE EQUILIBRIUM SEGREGATION OF HYDROGEN TO TILT BOUNDARIES IN NICKEL	179
N.R. Moody and S.M. Foiles	
CORRELATIONS BETWEEN GRAIN BOUNDARY STRUCTURE AND ENERGY	185
K.L. Merkle and D. Wolf	

*Invited Paper

HREM INVESTIGATION OF THE STRUCTURE OF THE $\Sigma 5(210)/$ [001] SYMMETRIC TILT GRAIN BOUNDARIES IN Nb G.H. Campbell, S.M. Foiles, Wayne E. King, M. Rühle, and W. Wien	191
*THE MECHANICAL BEHAVIOR OF A GRAIN BOUNDARY-RICH (NANO- CRYSTALLINE) METAL M.J. Mayo	197
INTERFACE STRUCTURE AND SLIP TRANSMISSION IN Ti-49Al-3Nb Daniel S. Schwartz and S.M.L. Sastry	207
ANALYSIS OF BRITTLE INTERGRANULAR CRACK PROPAGATION DURING STRESS CORROSION Russell H. Jones	213
THERMAL DESORPTION OF Hg MONOLAYERS FROM Cu(100) Y.J. Kime, Jiandi Zhang, and P.A. Dowben	221
GRAIN BOUNDARY STRUCTURE AND STRUCTURE-BEHAVIOR RELATIONSHIPS IN HCP METALS A.H. King	227
A PRELIMINARY CHARACTERIZATION OF THE DEFECT STRUCTURE OF THE ZETA PHASE IN THE INTERFACIAL REGION OF Fe-Zn COUPLES Lucille A. Giannuzzi, Paul R. Howell, Howard W. Pickering, and William R. Bitler	233
ON THE MICROSTRUCTURE OF A $\text{Ni}_3\text{Al/SiC/TiB}_2$ INTERMETALLIC MATRIX COMPOSITE PROCESSED BY SPRAY ATOMIZATION AND CO- DEPOSITION X. Liang and E.J. Lavernia	239
ANOMALY IN THE HALL COEFFICIENT OF Ag/Cr SUPERLATTICES Hideyuki Sato, Tadashi Kumano, Takeo Kaneko, and Ryoichi Yamamoto	245
SURFACE WAVE VELOCITY OF SILVER/CHROMIUM AND GOLD/ CHROMIUM SUPERLATTICES Takeo Kaneko, Shinzo Ogu, Kentaro Kyuno, Yasushi Inoue, Ryoichi Yamamoto, and Akira Yoshihara	249
GRAIN BOUNDARY SLIDING KINETICS AND STRESS RELAXATION PHENOMENA IN Ni ALLOYS F. Cosandey, S. Li, B. Cao, R. Schaller, and W. Benoit	255
STRUCTURAL RELAXATION BY PRECIPITATION IN Al-Li I. GROWTH KINETICS OF PRECIPITATES R. Kamel, N.K. Gobran, and M.M. Danial	261
PRECIPITATION AT TRANSFORMATION INTERFACES F.A. Khalid and D.V. Edmonds	273

*Invited Paper

GRAIN STRUCTURE INTERACTION BETWEEN COLD AND HOT SPUTTERED ALUMINUM FILMS David L. O'Meara	281
MORPHOLOGICAL STABILITY OF SEMICOHERENT SOLID-SOLID INTERFACES: A SIMPLE MODEL Craig Rottman	289
INTERFACIAL ENERGY REDUCTION ANALYSIS IN FIBROUS STRUCTURES A.C. Sandlin and R.J. Schaefer	295
*GRAIN BOUNDARY CHEMISTRY IN Al-Cu METALLIZATIONS AS DETERMINED BY ANALYTICAL ELECTRON MICROSCOPY J.R. Michael, A.D. Romig, Jr., and D.R. Frear	303
THE EFFECT OF DEPOSITION AND ANNEALING CONDITIONS ON THE MICROSTRUCTURE OF Al-Cu AND Al-Cu-Si THIN FILMS M. Park, S.J. Krause, and S.R. Wilson	313
THE EFFECT OF S SEGREGATION ON THE GRAIN BOUNDARY GEOMETRY OF A $\Sigma 11$ NICKEL BICRYSTAL Mary C. Juhas and Louiseette Priester	319
ON THE STRUCTURE OF TRANSFORMATION INTERFACES F.A. Khalid and D.V. Edmonds	325
*ROLE OF INTERFACES IN COARSENING AND GRAIN GROWTH S.P. Marsh and M.E. Glicksman	333
*GRAIN BOUNDARY STRUCTURE AND DIFFUSION INDUCED GRAIN BOUNDARY MIGRATION A.H. King	343
AUTHOR INDEX	355
SUBJECT INDEX	357

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Structure/Property Relationships for Metal/Metal Interfaces

RECONSTRUCTIONS AND MORPHOLOGICAL INSTABILITIES OF FCC (110) SURFACES

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ABSTRACT

We compare the ground state energy of the following structures of fcc (110) surfaces: the (1x1) flat surface, the (n x 1) reconstruction ($2 \leq n < \infty$), and the ($\infty \times 1$) structure where the surface is faceted into macroscopic (111) surfaces. We map out the phase diagram using a lattice model with pair and triplet interactions. We argue that it is unlikely that any realist pair potential will give a reconstructed ground state. We also doubt that including, in addition, three body interactions will stabilize the reconstructed structure for interatomic interactions derived from the embedded atom method.

INTRODUCTION

It has been clearly established that, at low temperatures, the (110) surface of certain fcc metals (Au, Pt, Ir) undergoes reconstructions into (n x 1) structures,¹ while many other fcc metals do not. A wide variety of theoretical techniques have been used to investigate the ground state structure of these surfaces and to compare with experimental results. On the one hand, it is useful to perform such calculations to test the success of theoretical techniques and models. On the other hand, one would like to have a more qualitative understanding of which structure is expected. The latter approach is taken here.

Two recent papers^{2,3} put forward simple arguments which give criteria to determine which of the (1x1) or (2x1) structures has the lower energy. Foiles² argues that the repulsive three body interactions stabilize the reconstructed phase, while Chen and Voter³ argue that a large second moment of missing bond distribution favors reconstruction. In both cases, it is argued that reconstruction occurs when the Cauchy discrepancy $C_{12} - C_{44}$ is large. Both authors argue that in those cases in which (2x1) is lower in energy than (1x1), (n x 1) reconstructions with $n > 2$ have a lower energy yet. Here we seek to investigate in more detail the lowest energy structure of (110) fcc surfaces.

FORMULATION

In the Embedded Atom Method (EAM) the energy of a system of identical atoms located at positions r_i may be written⁴

$$E = \sum_m F \left[\sum_{i \in m} \rho(R_{mi}) \right] + \frac{1}{2} \sum_{i,j} \phi(R_{ij}) , \quad (1)$$

(i ≠ j)

where F is the embedding function, $\rho(R_{ij})$ is the electron density at atom j a distance $R_{ij} = |r_i - r_j|$ from atom i , and $\phi(R_{ij})$ is the core-core pair repulsion. This may be rewritten²

$$E = E_0 + \sum_i \left[\sum_j J(R_{ij}) + \sum_j \sum_k T(R_{ij}, R_{jk}) + \sum_i \sum_j \sum_k Q(R_{ij}, R_{jk}, R_{ik}) + \dots \right] , \quad (2)$$

where n, i, j, k, \dots refer to distinct atomic sites and J, T, Q, \dots may be expressed in terms of F and ϕ . Graphically the interactions are of the "star" type, with site m in the middle and the "legs" going out to sites i, j, k, \dots

In this paper we make the major assumption that the atomic positions are restricted to the sites of an fcc lattice. Foiles² has found that this assumption has a small effect on the difference in energies between competing structures. In terms of the lattice gas variables $n = \pm 1$, Eq. (2) becomes

$$E = - \sum_m n_m \left[\sum_{i=1}^{\infty} J_i \sum_{p_1} n_{p_1} + \sum_{i=1}^{\infty} \sum_{j=1}^{\infty} T_{ij} \sum_{p_1} \sum_{p_j} n_{p_1} n_{p_j} + \sum_{i=1}^{\infty} \sum_{j=1}^{\infty} \sum_{k=1}^{\infty} Q_{ijk} \sum_{p_1} \sum_{p_j} \sum_{p_k} n_{p_1} n_{p_j} n_{p_k} + \dots \right] . \quad (3)$$

We require coexistence by demanding that both the solid phase (all $n_i = 1$) and the vapor phase (all $n_i = 0$) have the same reduced energy $E - \mu N$. From this we can determine the chemical potential μ . Then we calculate $E - \mu N$ with this μ for various surface structures. This gives the surface energy γ as a function the parameters $J_i, T_{ij}, Q_{ijk}, \dots$

The goal here is to investigate which phase of the $(1 \times n)$ structures has the lowest reduced energy at each point in coupling parameter space. To make this problem feasible and to increase our understanding of the various couplings, we look at small subsets of the full parameter set $\{J_i, T_{ij}, Q_{ijk}, \dots\}$. Foiles² has put forth a procedure by which these parameters may be determined using the EAM potentials. It will turn out that the (1×1) and $(\infty \times 1)$ phases are found in a large volume of

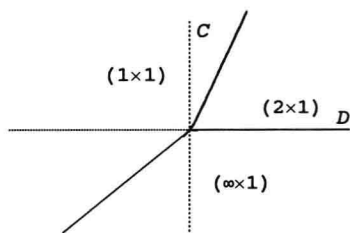


Fig. 1. Phase diagram of fcc (110) surfaces with pair interactions only, neglecting 9th and higher interactions. The model parameters C and D are defined in Eq. (5).

parameter space. Thus, a question we will address in detail is which parameters are needed to stabilize the (1×2) and (1×3) phases.

For convenience, instead of finding the true interface free energies ("surface tensions") per unit area $\tilde{\gamma}$, we find $\gamma = \tilde{\gamma}A$, where A is the area of the unit cell of the (1×1) surface, namely, $a^2/\sqrt{2}$, where a is the lattice constant.

PAIR INTERACTIONS ONLY

We begin by including pair (two body) interactions only, setting $T_{ij} = Q_{ijk} = \dots = 0$ in Eq. (3). We include pair interaction up to eighth neighbor, corresponding to a distance $2a$, which is $2\sqrt{2}$ longer than the nearest neighbor separation distance $a/\sqrt{2}$. In this case, bond counting gives

$$\gamma_{(1 \times 1)} = \gamma_{(\infty \times 1)} - C + D, \quad (4a)$$

$$\gamma_{(n \times 1)} = \gamma_{(\infty \times 1)} - C/n, \quad (4b)$$

where

$$\gamma_{(\infty \times 1)} = 6J_1 + 6J_2 + 24J_3 + 12J_4 + 36J_5 + 12J_6 + 72J_7 + 12J_8, \quad (5a)$$

$$C = 2J_2 + 4J_3 + 16J_5 + 4J_6 + 16J_7 + 8J_8, \quad (5b)$$

$$D = 4J_5 + 8J_7 + 2J_8. \quad (5c)$$

Note that, of the many model parameters J_1, \dots, J_8 , the parameters arise in such a combination that only two parameters, C and D , are needed to determine the phase. This greatly simplifies the analysis. The resulting phase diagram is given in Fig. 1.

Several conclusions may be drawn from these results. It appears unlikely any realistic model of an fcc metal will arise which has pair interactions only and has a (2×1) ground state. Such a model must satisfy $D > \frac{1}{2}C > 0$. Note that D depends on fifth neighbor pairs and higher. At the fifth neighbor